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March 2015

## FDD86252

## N-Channel Shielded Gate PowerTrench<sup>®</sup> MOSFET 150 V, 27 A, 52 m $\Omega$

#### **Features**

- Shielded Gate MOSFET Technology
- Max  $r_{DS(on)}$  = 52 m $\Omega$  at  $V_{GS}$  = 10 V,  $I_D$  = 5 A
- Max  $r_{DS(on)}$  = 72 m $\Omega$  at  $V_{GS}$  = 6 V,  $I_D$  = 4 A
- 100% UIL tested
- RoHS Compliant

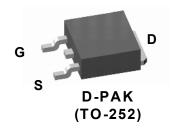


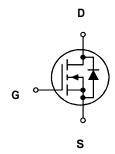
#### **General Description**

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench® process that incorporates Shielded Gate technology. This process has been optimized for the on-state resistance and yet maintain superior switching performance.

### **Application**

■ DC - DC Conversion





## **MOSFET Maximum Ratings** $T_C = 25$ °C unless otherwise noted

Symbol	Parameter			Ratings	Units
$V_{DS}$	Drain to Source Voltage			150	V
$V_{GS}$	Gate to Source Voltage			±20	V
	Drain Current -Continuous	T <sub>C</sub> = 25 °C		27	
$I_D$	-Continuous	T <sub>A</sub> = 25 °C	(Note 1a)	5	Α
	-Pulsed		(Note 4)	30	
E <sub>AS</sub>	Single Pulse Avalanche Energy		(Note 3)	72	mJ
D	Power Dissipation	T <sub>C</sub> = 25 °C		89	W
$P_{D}$	Power Dissipation	T <sub>A</sub> = 25 °C	(Note 1a)	3.1	VV
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature	Range		-55 to +150	°C

#### **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction to Case	1.4	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a	40	C/VV

#### **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD86252	FDD86252	D-PAK(TO-252)	13 "	16 mm	2500 units

## Electrical Characteristics T<sub>J</sub> = 25 °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	150			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, referenced to 25 °C		104		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 120 V, V <sub>GS</sub> = 0 V			1	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	V <sub>GS</sub> = ±20 V, V <sub>DS</sub> = 0 V			±100	nA

#### On Characteristics

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	2.0	3.1	4.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, referenced to 25 °C		-10		mV/°C
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 5 A		41	52	
r <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 6 \text{ V}, I_D = 4 \text{ A}$		49	72	mΩ
		$V_{GS}$ = 10 V, $I_{D}$ = 5 A, $T_{J}$ = 125 °C		81	103	
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 5 A		15		S

#### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	75.77.7	741	985	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = 75 V, V <sub>GS</sub> = 0 V, f = 1 MHz	78	130	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1 1011 12	4.2	10	pF
Ra	Gate Resistance		0.4		Ω

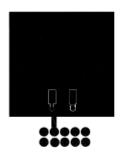
#### **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time			8.3	17	ns
t <sub>r</sub>	Rise Time	V <sub>DD</sub> = 75 V, I <sub>D</sub> = 5 A,		1.8	10	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS}$ = 10 V, $R_{GEN}$ = 6 $\Omega$		14	25	ns
t <sub>f</sub>	Fall Time			3	10	ns
$Q_g$	Total Gate Charge	V <sub>GS</sub> = 0 V to 10 V		11.3	16	nC
$Q_{g}$	Total Gate Charge	$V_{GS} = 0 \text{ V to 5 V}$ $V_{DD} = 7$	75 V,	6.3	9	nC
$Q_{gs}$	Gate to Source Charge	I <sub>D</sub> = 5 A	4	3.4		nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge			2.6		nC

#### **Drain-Source Diode Characteristics**

$V_{SD}$	I Source-Drain Dione Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 5 \text{ A}$ (Note 2)	0.80	1.3	V
		$V_{GS} = 0 \text{ V}, I_S = 2.6 \text{ A}$ (Note 2)	0.77	1.2	
t <sub>rr</sub>	Reverse Recovery Time	I <sub>E</sub> = 5 A. di/dt = 100 A/μs	60	97	ns
Q <sub>rr</sub>	Reverse Recovery Charge	TIF - 5 A, αι/αι - 100 A/μs	72	115	nC

<sup>1:</sup> R<sub>0,JA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>0,JC</sub> is guaranteed by design while R<sub>0,JA</sub> is determined by the user's board design.



a) 40 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper



b) 96 °C/W when mounted on

- Pulse Test: Pulse Width < 300 μs, Duty cycle < 2.0%.</li>
   Starting T<sub>J</sub> = 25 °C, L = 1 mH, I<sub>AS</sub> = 12 A, V<sub>DD</sub> = 135 V, V<sub>GS</sub> = 10 V.
   Pulsed Drain current is tested at 300 μs with 2% duty cycle. For repetitive pulses, the pulse width is limited by the maximum junction temperature.

#### Typical Characteristics T<sub>J</sub> = 25 °C unless otherwise noted

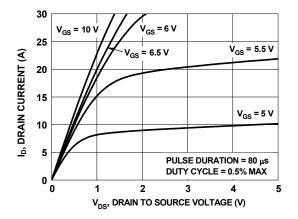


Figure 1. On-Region Characteristics

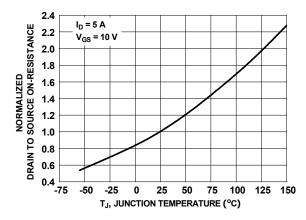


Figure 3. Normalized On-Resistance vs Junction Temperature

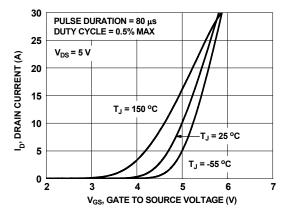


Figure 5. Transfer Characteristics

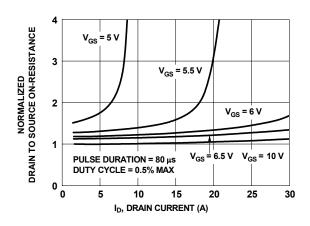


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

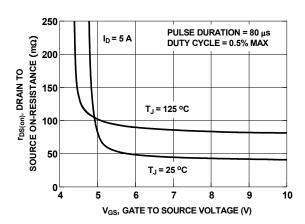


Figure 4. On-Resistance vs Gate to Source Voltage

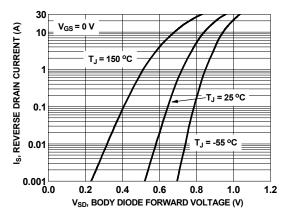


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

## Typical Characteristics $T_J$ = 25 $^{\circ}$ C unless otherwise noted

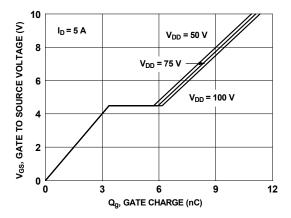


Figure 7. Gate Charge Characteristics

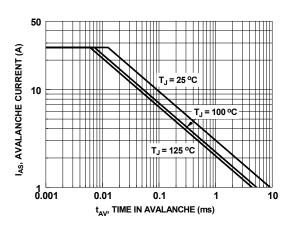


Figure 9. Unclamped Inductive Switching Capability

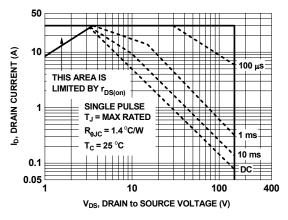


Figure 11. Forward BiasSafe Operating Area

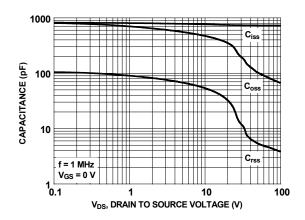


Figure 8. Capacitance vs Drain to Source Voltage

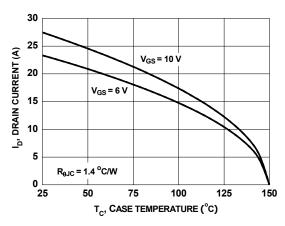


Figure 10. Maximum Continuous Drain Current vs Case Temperature

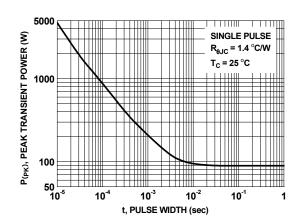


Figure 12. Single Pulse Maximum Power Dissipation

## Typical Characteristics T<sub>J</sub> = 25 °C unless otherwise noted

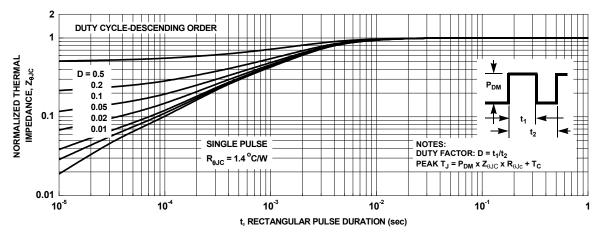
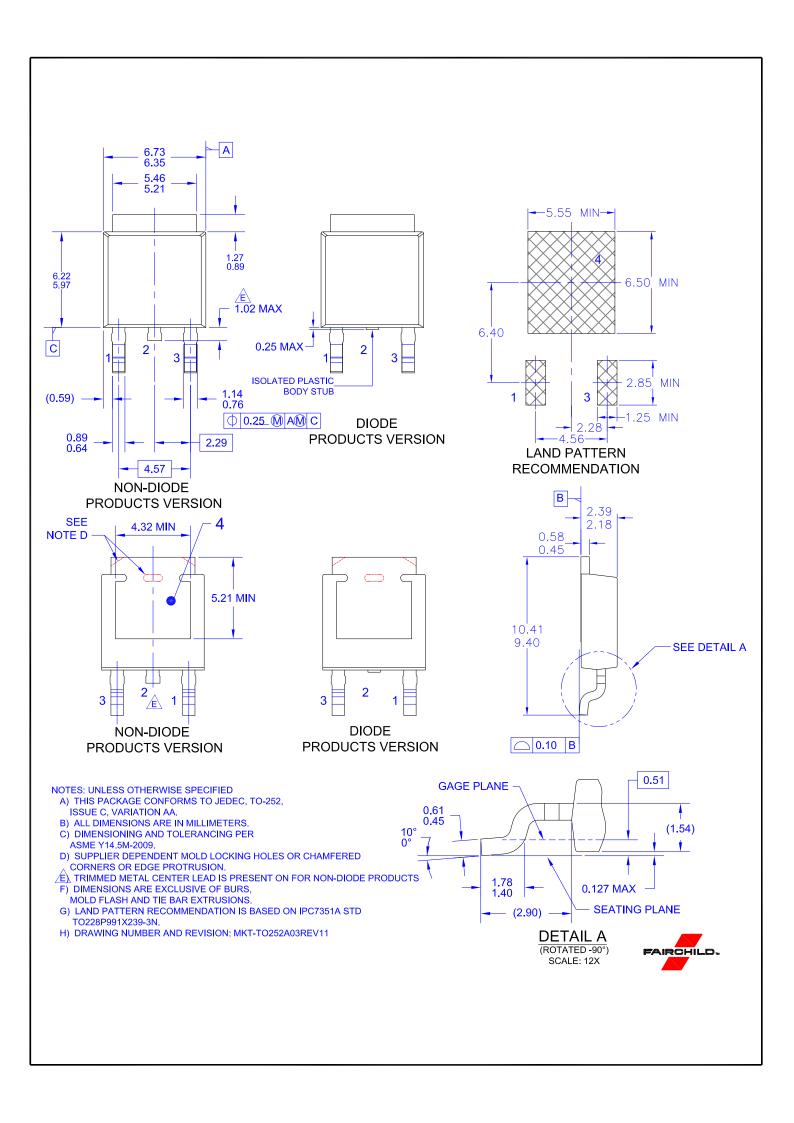


Figure 13. Junction-to-Case Transient Thermal Response Curve



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